

<b>Notice of References Cited</b>	Application/Control No. 10/752,269	Applicant(s)/Patent Under Reexamination DELANG ET AL.	
	Examiner Scott A. Rogers	Art Unit 2625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0094170 A1	05-2005	Ichitani, Shuji	358/1.9
*	B	US-2003/0123072 A1	07-2003	Spronk, Conemelis Adrianus Maria	358/1.9
*	C	US-2001/0028471 A1	10-2001	Hirokazu, Kondo	358/1.13
*	D	US-6,891,649 B1	05-2005	Kondo, Hirokazu	358/1.9
*	E	US-6,320,668 B1	11-2001	Kim, Eun-Jin	358/504
*	F	US-7,206,094 B2	04-2007	Kumada et al.	358/1.16
*	G	US-2004/0184658 A1	09-2004	Inoue, Yuuki	358/1.9
*	H	US-6,324,975 B1	12-2001	Kondo, Hirokazu	101/171
*	I	US-2003/0151757 A1	08-2003	Bestmann et al.	358/1.9
*	J	US-7,233,412 B2	06-2007	Siegeritz, Helmut	358/1.9
*	K	US-7,009,732 B2	03-2006	Mayer et al.	358/1.9
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

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